## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | LAIR, JOHN | Examiner | Art Unit | Wayne Cai | 2681 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-US 20040198436A1	10-2004	Alden, Richard P	455/556.1
	В	US-2002/0057746 A1	05-2002	Chen, Weizhong	375/334
	С	US-5,101,504 A	03-1992	Lenz, Vernon C.	455/78
	D	US-6,795,718 B2	09-2004	Bae, Hyon S.	455/575.2
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ī	US-		,	
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0	_				
	Р	•				
	Q.					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.